# MOS FIELD EFFECT TRANSISTOR $\mu PA2451C$

# N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

# DESCRIPTION

NEC

The  $\mu$  PA2451C is a switching device, which can be driven directly by a 2.5 V power source.

The  $\mu$  PA2451C features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

### FEATURES

- 2.5 V drive available
- · Low on-state resistance
- $\begin{array}{l} {R_{DS(on)1}=20.0\ m\Omega\ MAX.\ (V_{GS}=4.5\ V,\ I_{D}=4.0\ A)} \\ {R_{DS(on)2}=21.0\ m\Omega\ MAX.\ (V_{GS}=4.0\ V,\ I_{D}=4.0\ A)} \\ {R_{DS(on)3}=25.0\ m\Omega\ MAX.\ (V_{GS}=3.1\ V,\ I_{D}=4.0\ A)} \\ {R_{DS(on)4}=32.0\ m\Omega\ MAX.\ (V_{GS}=2.5\ V,\ I_{D}=4.0\ A)} \end{array}$
- Built-in G-S protection diode against ESD

### ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

| VDSS     | 30.0   | V  |
|----------|--|--|
| Vgss     | ±12.0  | V  |
| D(DC)    | ±8.2   | Α  |
| D(pulse) | ±60.0  | А  |
| Pt1      | 2.5  | W  |
| Pt2      | 0.7  | W  |
| Tch      | 150  | °C   |
| Tstg     | -55 to +150                                      | °C   |
|          | VGSS<br>ID(DC)<br>ID(pulse)<br>PT1<br>PT2<br>Tch | VGSS ±12.0   ID(DC) ±8.2   ID(pulse) ±60.0   PT1 2.5   PT2 0.7   Tch 150 |

Notes 1. Mounted on ceramic board of 50 cm<sup>2</sup> x 1.1 mmt

- **2.** PW  $\leq$  10  $\mu$ s, Duty Cycle  $\leq$  1%
- 3. Mounted on FR-4 board of 50 cm<sup>2</sup> x 1.1 mmt

# ORDERING INFORMATION

| PART NUMBER                          | LEAD PLATING PACKING |             | PACKAGE           |  |  |  |  |  |  |
|--------------------------------------|----------------------|-------------|-------------------|--|--|--|--|--|--|
| μ PA2451CTL-E1-A <sup>Note</sup>     |                      | Reel        |                   |  |  |  |  |  |  |
| $\mu$ PA2451CTL-E2-A <sup>Note</sup> | Sn-Bi                | 3000 p/reel | 6PIN HWSON (4521) |  |  |  |  |  |  |

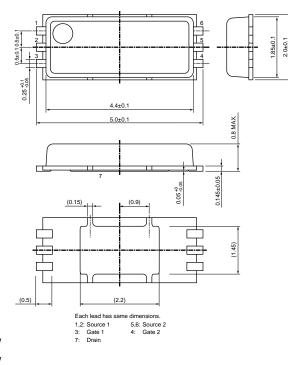
Note Pb-free (This product does not contain Pb in the external electrode and other parts.)

**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

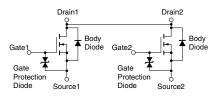
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# PACKAGE DRAWING (Unit: mm)



# EQUIVALENT CIRCUIT

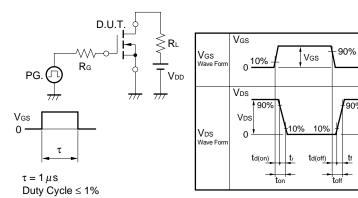


| CHARACTERISTICS                                     | SYMBOL               | TEST CONDITIONS                                   | MIN. | TYP. | MAX.  | UNIT |
|---|----------------------|---|------|------|-------|------|
| Zero Gate Voltage Drain Current                     | IDSS                 | V <sub>DS</sub> = 30.0 V, V <sub>GS</sub> = 0 V   |      |      | 1.0   | μA   |
| Gate Leakage Current                                | lgss                 | V <sub>GS</sub> = ±12.0 V, V <sub>DS</sub> = 0 V  |      |      | ±10.0 | μA   |
| Gate to Source Cut-off Voltage                      | V <sub>GS(off)</sub> | V <sub>DS</sub> = 10.0 V, I <sub>D</sub> = 1.0 mA | 0.50 |      | 1.50  | V    |
| Forward Transfer Admittance Note                    | y <sub>fs</sub>      | V <sub>DS</sub> = 10.0 V, I <sub>D</sub> = 4.0 A  | 6.0  |      |       | S    |
| Drain to Source On-state Resistance <sup>Note</sup> | RDS(on)1             | V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 4.0 A   | 12.0 | 17.5 | 20.0  | mΩ   |
|   | RDS(on)2             | V <sub>GS</sub> = 4.0 V, I <sub>D</sub> = 4.0 A   | 12.5 | 18.0 | 21.0  | mΩ   |
|   | RDS(on)3             | V <sub>GS</sub> = 3.1 V, I <sub>D</sub> = 4.0 A   | 14.0 | 21.0 | 25.0  | mΩ   |
|   | RDS(on)4             | V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 4.0 A   | 15.5 | 25.5 | 32.0  | mΩ   |
| Input Capacitance                                   | Ciss                 | V <sub>DS</sub> = 10.0 V,                         |      | 605  |       | pF   |
| Output Capacitance                                  | Coss                 | V <sub>GS</sub> = 0 V,                            |      | 87   |       | pF   |
| Reverse Transfer Capacitance                        | Crss                 | f = 1.0 MHz                                       |      | 40   |       | pF   |
| Turn-on Delay Time                                  | td(on)               | V <sub>DD</sub> = 15.0 V,                         |      | 40   |       | ns   |
| Rise Time   | tr                   | I <sub>D</sub> = 4.0 A,                           |      | 75   |       | ns   |
| Turn-off Delay Time                                 | td(off)              | V <sub>GS</sub> = 4.0 V,                          |      | 140  |       | ns   |
| Fall Time   | tr                   | R <sub>G</sub> = 6 Ω                              |      | 85   |       | ns   |
| Total Gate Charge                                   | QG                   | V <sub>DD</sub> = 24.0 V,                         |      | 6.3  |       | nC   |
| Gate to Source Charge                               | Q <sub>GS</sub>      | V <sub>GS</sub> = 4.0 V,                          |      | 1.5  |       | nC   |
| Gate to Drain Charge                                | Qgd                  | I <sub>D</sub> = 8.2 A                            |      | 2.3  |       | nC   |
| Body Diode Forward Voltage Note                     | VF(S-D)              | IF = 8.2 A, VGS = 0 V                             |      | 0.86 |       | V    |

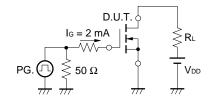
# ELECTRICAL CHARACTERISTICS (TA = 25°C)

**Note** Pulsed: PW  $\leq$  350  $\mu$ s, Duty Cycle  $\leq$  2%

# **TEST CIRCUIT 1 SWITCHING TIME**

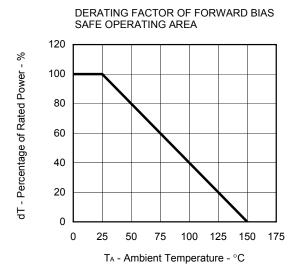


# TEST CIRCUIT 2 GATE CHARGE

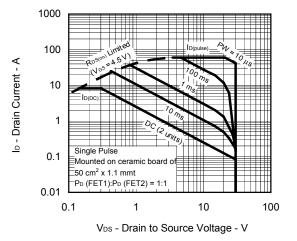


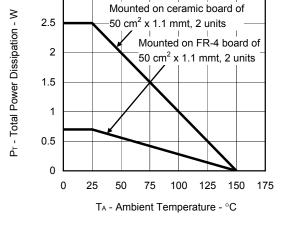
90%

# ELECTRICAL CHARACTERISTICS (TA = 25°C)







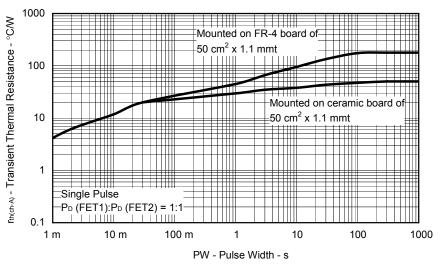


TOTAL POWER DISSIPATION vs.

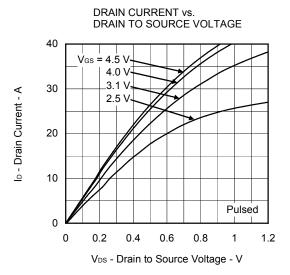
AMBIENT TEMPERATURE

3

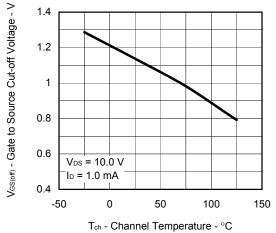
### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



Data Sheet G18793EJ1V0DS

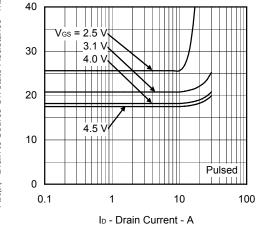




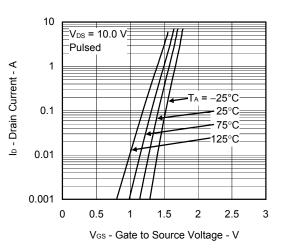




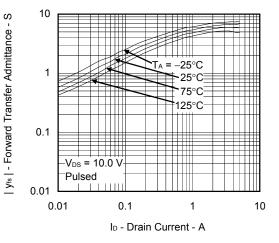




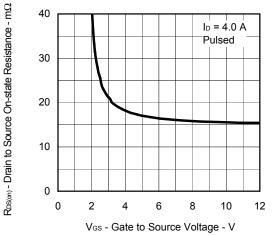
FORWARD TRANSFER CHARACTERISTICS

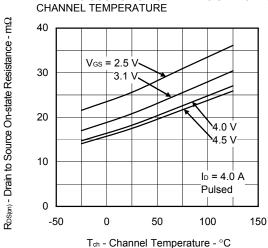


FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



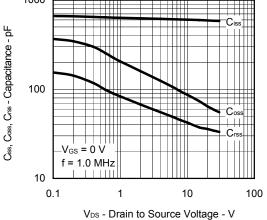
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE





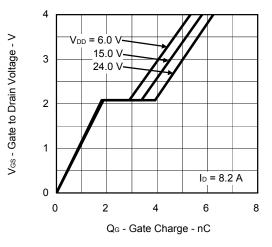
DRAIN TO SOURCE ON-STATE RESISTANCE vs.

CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE

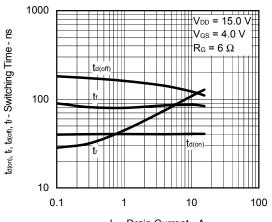


1000

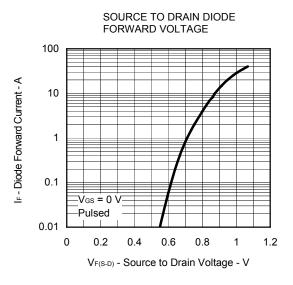
DYNAMIC INPUT CHARACTERISTICS









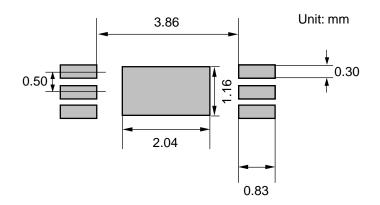


Data Sheet G18793EJ1V0DS

## <Notes for using this device safely>

When you use this device, in order to prevent a customer's hazard and damage, use it with understanding the following contents. If used exceeding recommended conditions, there is a possibility of causing failure of the device and characteristic degradation.

- 1. When you mount the device on a substrate, carry out within our recommended soldering conditions of infrared reflow. If mounted exceeding the conditions, the characteristic of a device may be degraded and it may result in failure.
- 2. When you wash the device mounted the substrate, carry out within our recommended conditions. If washed exceeding the conditions, the characteristic of a device may be degraded and it may result in failure.
- 3. When you use ultrasonic wave to substrate after the device mounting, prevent from touching a resonance generator directly. If it touches, the characteristic of a device may be degraded and it may result in failure.
- 4. Please refer to **Figure 1** as an example of the land pattern. Optimize the land pattern in consideration of density, appearance of solder fillets, common difference, etc in an actual design.



### Figure 1. Example of the land pattern

- NEC
  - 5. This device is very thin device and should be handled with caution for mechanical stress. The rate of distortion applied to the device should become below 2000  $\mu\epsilon$ .<sup>Note1</sup> If the rate of distortion exceeds 2000  $\mu\epsilon$ , the characteristic of a device may be degraded and it may result in failure.

### Figure 2. Direction of substrate and stress

The substrate that mounted the device is on a stand with a support width of 24 mm. The device is turned downward. The stress is applied from a top.

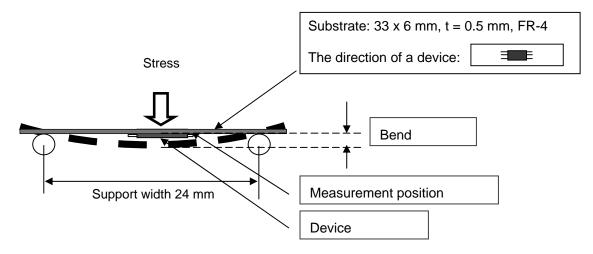
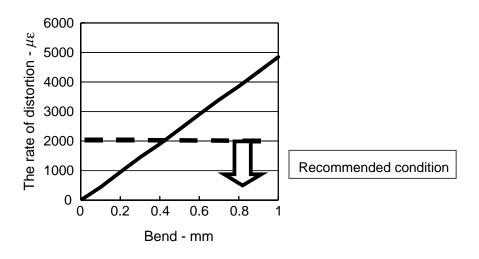
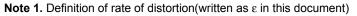


Figure 3. Example of the bend and the rate of distortion Note2





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\epsilon = (I - I_0)/I_0
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- lo: Distance for two arbitrary points before receiving stress.
- I: Distance above-mentioned when receiving stress.
- 2. The relation of the distortion and the bend changes with several conditions, such as a size of substrate and so on.

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